

**Search Notes**

Application/Control No.

10/664,897

Examiner

Phuoc Tran

Applicant(s)/Patent under  
Reexamination

HAYASHI, YUKIO

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
382	246, 233	6/4/2007	PT
375	240.27,		
	240.28		
348	425.2,		
	425.4		
341	67, 94		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR